Cascade | Z | Probe

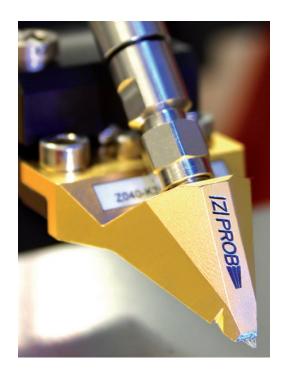
RF and Microwave Wafer Probes

Overview

The |Z| Probe family of RF and microwave wafer probes revolutionized the way you test your HF devices. Contacting your device under test (DUT) has never been easier and uses less overtravel than other wafer probes, which means less crashes and a longer probe life. In fact, the |Z| Probe is guaranteed to last for over 1,000,000 contacts.

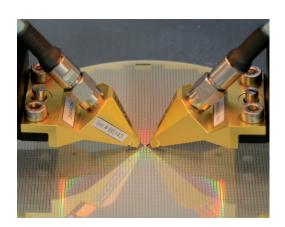
The IZI Probe family has been now further enhanced with the innovative 1MXTM technology. Electrical performance, especially insertion and return loss, has been advanced to levels superior to older technologies like thin-film and microcoax probes. In addition, isolation (crosstalk) has been significantly improved resulting in a probe that delivers the highest accuracy for your wafer-level RF and microwave measurements.

To calibrate your probes, we offer the powerful SussCal® Calibration Software and the highly-accurate CSR family of calibration substrates.



> |Z| Probe GS / SG

Frequency	10 GHz	20 GHz
1MX technology	-	✓
Pitches (μm)	550 to 1250 μm*	50 to 500 μm*
Body		
• Slim case	K1N	K1N
Slim case high temp / cryo	Y1N	Y1N
Standard case	K3N	K3N
Standard case high temp	Y3N	Y3N
Oblique left / right	KRN/KLN	-



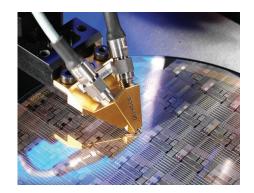
> |Z| Probe GSG

Frequency	40 GHz	50 GHz	67 GHz
1MX technology	/**	✓	\checkmark
Pitches (µm)	550 to 1250 μm*	50 to 500 μm*	50 to 250 μm*
Body			
Slim case	K1N	A1N	V1N
• Slim case high temp / cryo	Y1N	B1N	C1N
Standard case	K3N	A3N	V3N
Standard case high temp	Y3N	B3N	C3N
Oblique left / right	KRN/KLN	-	-



> Dual |Z| Probe

	GSGSG	GSSG / SGS
Frequency	40 GHz / 50 GHz	18 GHz
1MX technology	\checkmark	✓
Pitches (μm)	100 to 500 μm*	100 to 500 μm*
Body		
Standard case	K3N / A3N	K3N
 High temp / cryo 	Y3N / B3N	Y3N



> |Z| Probe Power GSG

(For High Power / Low Loss Applications)

Frequency	40 GHz
Pitches (µm)	100 to 500 μm*
Body	
Slim case with 2.92 mm connector	K1A
Standard case with 2.92 mm connector	КЗА
Slim case with 2.4 mm connector	A1A
Standard case with 2.92 mm connector	A3A



Data, design and specification depend on individual process conditions and can vary according to equipment configurations. Not all specifications may be valid simultaneously.



^{*}See datasheet for exact specifications. Custom pitches and footprints are available on request. ** 1MX technology is available for pitches up to 500 $\mu m.$

> Multi-IZI Probe

	GSG	GS / SG, SS
Frequency	Up to 15 GHz	Up to 6 GHz
Digital applications	Up to 25 GHz	Up to 7.5 GHz
Pitches (μm)	100, 125, 150, 200,	100, 125, 150, 200,
	250, 500 μm	250, 500 μm
Number of contacts		
• 100 to 200 μm	Up to 35 contacts	On request
• 250 μm	25 contacts	On request
• 500 μm	Up to 7 contacts	On request



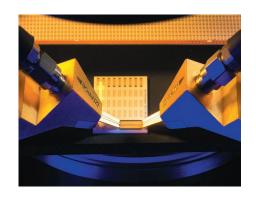
> |Z| Probe Oblique

	GSG	GS / SG	
Frequency	40 GHz	10 GHz	
Pitches (μm)	100, 125, 150,	100, 125, 150,	
	200, 250 μm	200, 250 μm	
Body			
• Left	KLN	KLN	
• Right	KRN	KRN	



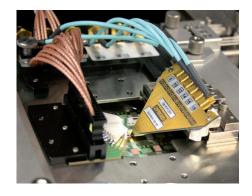
> |Z| Probe PCB

	GSG / GS / SG
Frequency	GSG / SG: 4 GHz
	GSG: Up to 20 GHz
Pitches (μm)	500, 650, 800, 1000, 1250, 1500, 2000, 2500 μm 350 to 4500 μm available upon request
Body	
Slim case	P1S
Standard case	P3S



> |Z| Probe Card

Minimum 4.5 inch in diameter	
Minimum 4.5 inch	
NESW	
Z Probe GS/SG	
Z Probe	
Dual Z Probe Multi Z Probe	
Z Probe Power	
	Minimum 4.5 inch NESW IZI Probe GS/SG IZI Probe Dual IZI Probe Multi IZI Probe



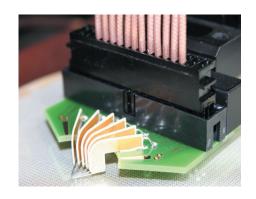
> HF Probe Wedge

Available with	Z Probe GS/SG
	Z Probe
	Dual Z Probe Multi Z Probe
	Z Probe Power



> DC Probe Wedge

Kelvin	Up to eight microstrip blades
DC	Up to 20 blades (microstrip, ceramic or metal)
	Others on request



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